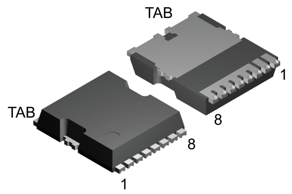
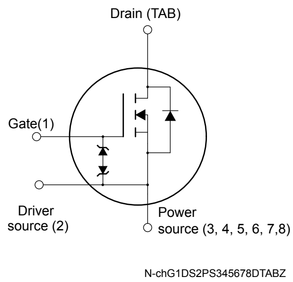
STO33N60M6

Datasheet

N-channel 600 V, 105 mΩ typ., 25 A, MDmesh M6 Power MOSFET in a TO-LL package



TO-LL type A



Product status link
STO33N60M6

Product summary	
Order code	STO33N60M6
Marking	33N60M6
Package	TO-LL type A
Packing	Tape and reel

Features

Order code	V_{DS}	$R_{DS(on)}$ max.	I_D
STO33N60M6	600 V	125 mΩ	25 A

- Reduced switching losses
- Lower $R_{DS(on)}$ per area vs previous generation
- Low gate input resistance
- 100% avalanche tested
- Zener-protected
- Excellent switching performance thanks to the extra driving source pin

Applications

- Switching applications
- LLC converters
- Boost PFC converters

Description

The new MDmesh M6 technology incorporates the most recent advancements to the well-known and consolidated MDmesh family of SJ MOSFETs. STMicroelectronics builds on the previous generation of MDmesh devices through its new M6 technology, which combines excellent $R_{DS(on)}$ per area improvement with one of the best effective switching behaviors available, as well as a user-friendly experience for maximum end-application efficiency.

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{GS}	Gate-source voltage	±25	V
I_D	Drain current (continuous) at T_C = 25 °C	25	A
	Drain current (continuous) at T_C = 100 °C	15.8	
I_{DM} (1)	Drain current (pulsed)	78	A
P_{TOT}	Total power dissipation at T_C = 25 °C	230	W
dv/dt (2)	Peak diode recovery voltage slope	15	V/ns
dv/dt (3)	MOSFET dv/dt ruggedness	100	V/ns
T_{stg}	Storage temperature range	-55 to 150	°C
T_J	Operating junction temperature range		°C

1. *Pulse width limited by safe operating area.*
2. *I_{SD} ≤ 25 A, di/dt ≤ 400 A/µs, V_{DS} (peak) < $V_{(BR)DSS}$, V_{DD} = 400 V.*
3. *V_{DS} ≤ 480 V.*

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance, junction-to-case	0.54	°C/W
R_{thJB}	Thermal resistance, junction-to-board (1)	43	°C/W
	Thermal resistance, junction-to-board (2)	22	

1. *When mounted on 1 inch² FR-4 pcb, standard footprint 2 Oz copper board.*
2. *When mounted on 40x40mm FR-4 pcb, 6 cm² 2 Oz copper board.*

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
I_{AR}	Avalanche current, repetitive or non-repetitive (pulse width limited by T_J max.)	4	A
E_{AS}	Single pulse avalanche energy (starting T_J = 25 °C, I_D = I_{AR}, V_{DD} = 50 V)	500	mJ

2 Electrical characteristics

T_C = 25 °C unless otherwise specified.

Table 4. On/off states

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	V_{GS} = 0 V, I_D = 1 mA	600			V
I_{DSS}	Zero gate voltage drain current	V_{GS} = 0 V, V_{DS} = 600 V			1	µA
		V_{GS} = 0 V, V_{DS} = 600 V, T_C = 125 °C [(1)]			100	
I_{GSS}	Gate-body leakage current	V_{DS} = 0 V, V_{GS} = ±25 V			±5	µA
$V_{GS(th)}$	Gate threshold voltage	V_{DS} = V_{GS}, I_D = 250 µA	3.25	4.00	4.75	V
$R_{DS(on)}$	Static drain-source on-resistance	V_{GS} = 10 V, I_D = 12.5 A		105	125	mΩ

1. *Defined by design, not subject to production test.*

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{iss}	Input capacitance	V_{DS} = 100 V, f = 1 MHz, V_{GS} = 0 V	-	1515	-	pF
C_{oss}	Output capacitance		-	128	-	
C_{rss}	Reverse transfer capacitance		-	4.2	-	
$C_{oss\ eq.}$ [(1)]	Equivalent output capacitance	V_{DS} = 0 to 480 V, V_{GS} = 0 V	-	269	-	pF
R_G	Intrinsic gate resistance	f = 1 MHz, I_D = 0 A	-	1.5	-	Ω
Q_g	Total gate charge	V_{DD} = 480 V, I_D = 25 A, V_{GS} = 0 to 10 V (see Figure 14. Test circuit for gate charge behavior)	-	33.4	-	nC
Q_{gs}	Gate-source charge		-	9.7	-	
Q_{gd}	Gate-drain charge		-	14	-	

1. *$C_{oss\ eq.}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.*

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	V_{DD} = 300 V, I_D = 12.5 A, R_G = 4.7 Ω, V_{GS} = 10 V (see Figure 13. Switching times test circuit for resistive load and Figure 18. Switching time waveform)	-	19.5	-	ns
t_r	Rise time		-	33	-	
$t_{d(off)}$	Turn-off delay time		-	38.5	-	
t_f	Fall time		-	7.5	-	

Table 7. **Source-drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain current		-		25	A
I_{SDM} (1)	Source-drain current (pulsed)		-		78	A
V_{SD} (2)	Forward on voltage	I_{SD} = 25 A, V_{GS} = 0 V	-		1.6	V
t_{rr}	Reverse recovery time	I_{SD} = 25 A, di/dt = 100 A/µs,	-	265		ns
Q_{rr}	Reverse recovery charge	V_{DD} = 60 V	-	3.07		µC
I_{RRM}	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	23.2		A
t_{rr}	Reverse recovery time	I_{SD} = 25 A, di/dt = 100 A/µs,	-	374		ns
Q_{rr}	Reverse recovery charge	V_{DD} = 60 V, T_J = 150 °C	-	5.78		µC
I_{RRM}	Reverse recovery current	(see Figure 15. Test circuit for inductive load switching and diode recovery times)	-	30.9		A

1. *Pulse width is limited by safe operating area.*
2. *Pulsed: pulse duration = 300 µs, duty cycle 1.5%.*

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

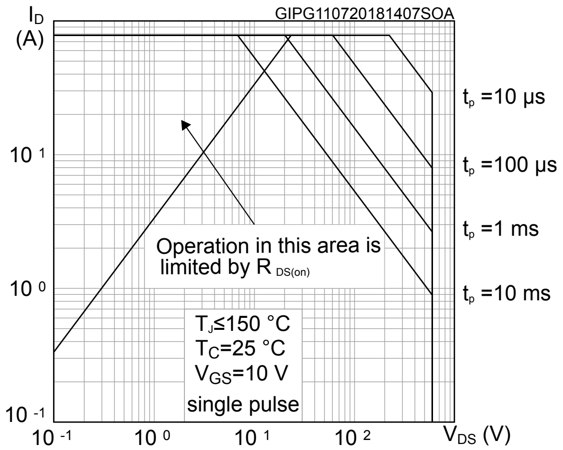


Figure 2. Thermal impedance

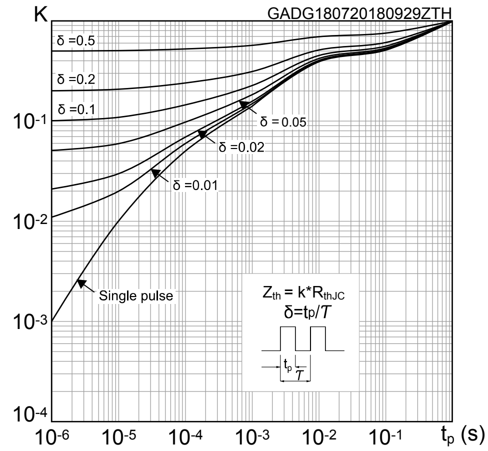


Figure 3. Output characteristics

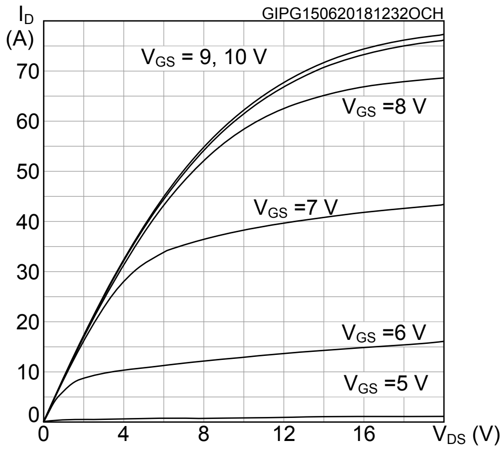


Figure 4. Transfer characteristics

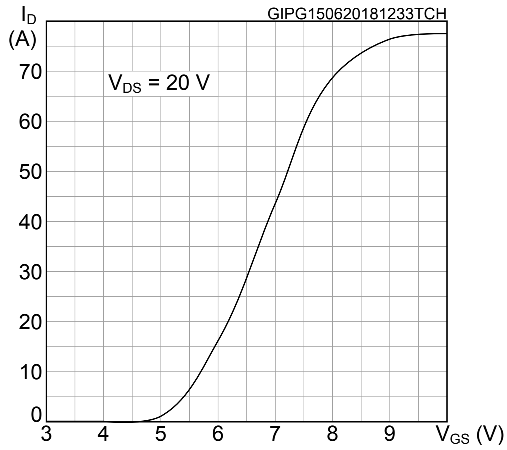


Figure 5. Gate charge vs gate-source voltage

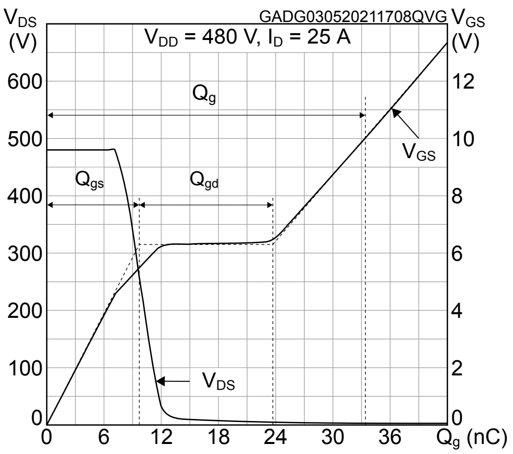


Figure 6. Static drain-source on-resistance

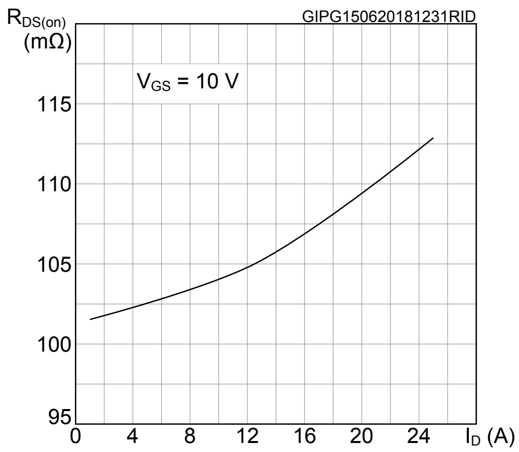


Figure 7. Capacitance variations

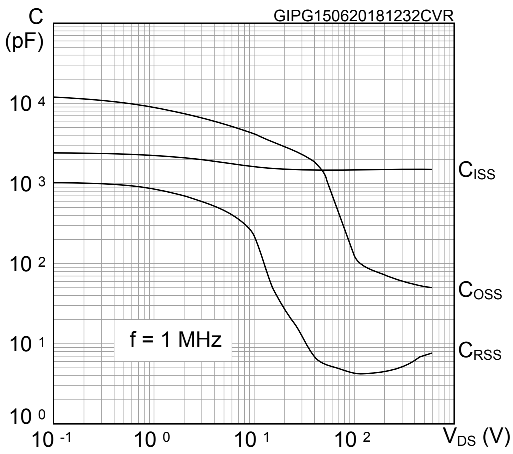


Figure 8. Normalized gate threshold voltage vs temperature

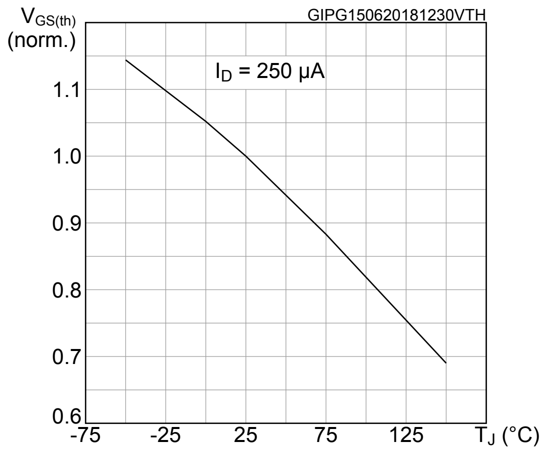


Figure 9. Normalized on-resistance vs temperature

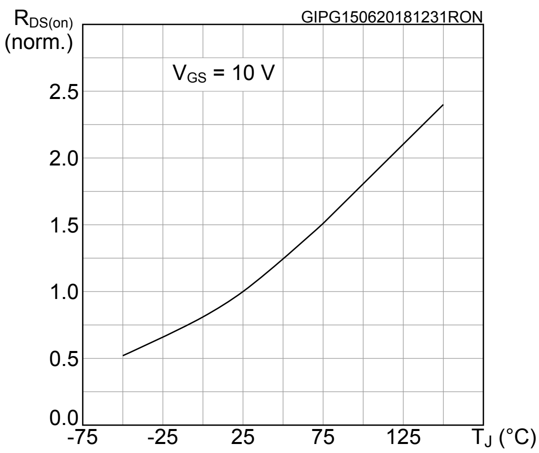


Figure 10. Normalized $V_{(BR)DSS}$ vs temperature

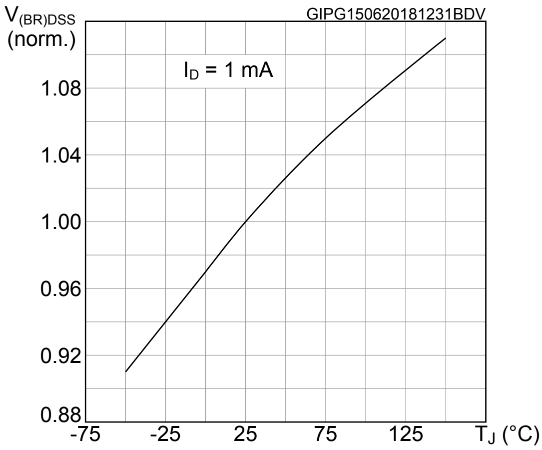


Figure 11. Output capacitance stored energy

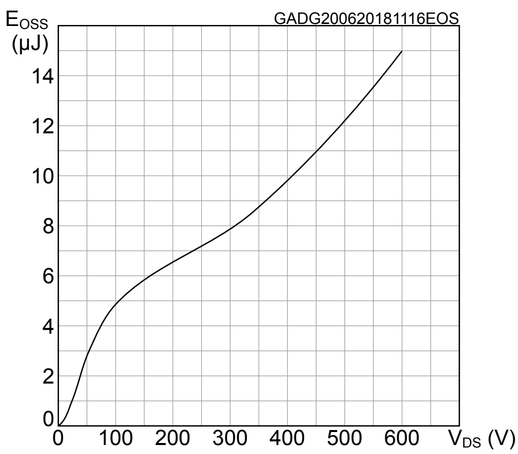
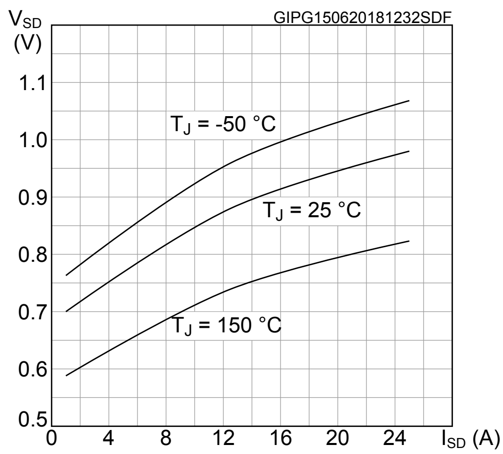


Figure 12. Source-drain diode forward characteristics



3 Test circuits

Figure 13. Switching times test circuit for resistive load

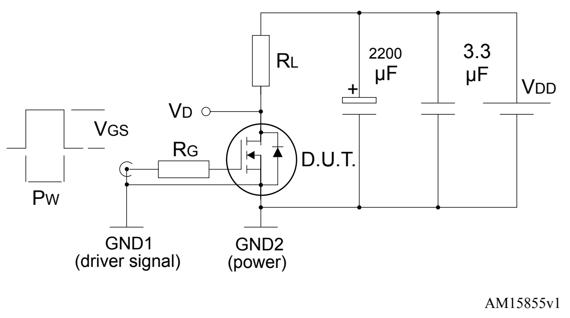


Figure 14. Test circuit for gate charge behavior

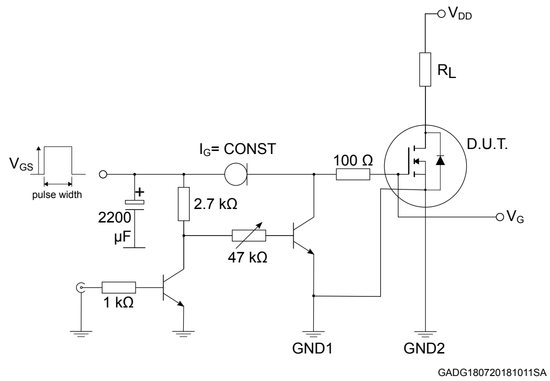


Figure 15. Test circuit for inductive load switching and diode recovery times

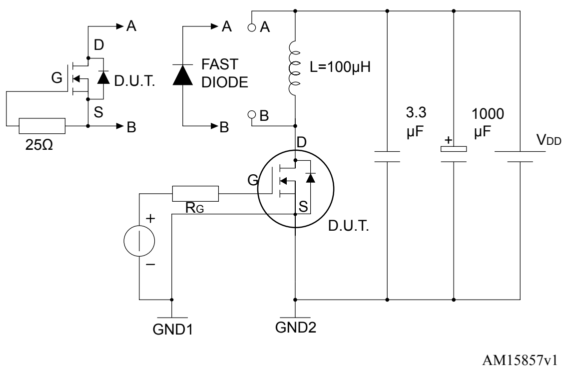


Figure 16. Unclamped inductive load test circuit

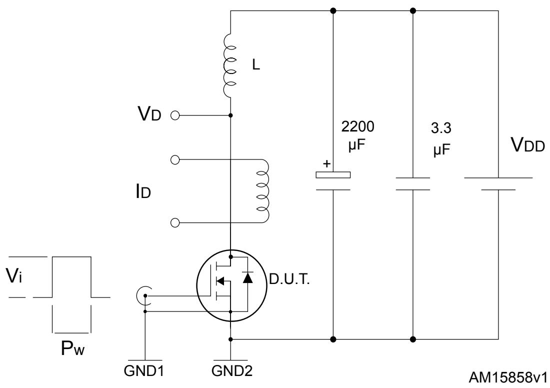


Figure 17. Unclamped inductive waveform

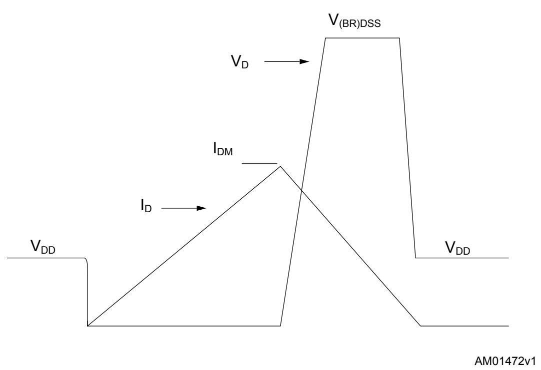
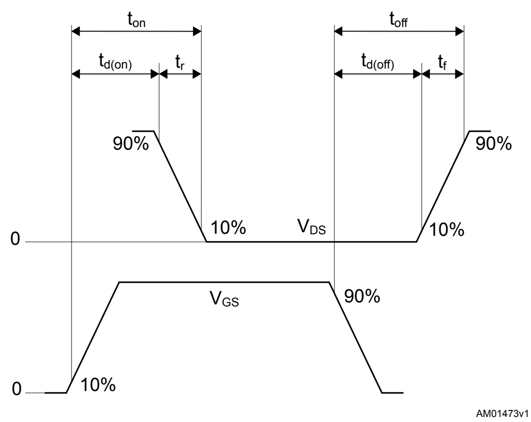


Figure 18. Switching time waveform



4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

4.1 TO-LL type A package information

Figure 19. TO-LL type A package outline

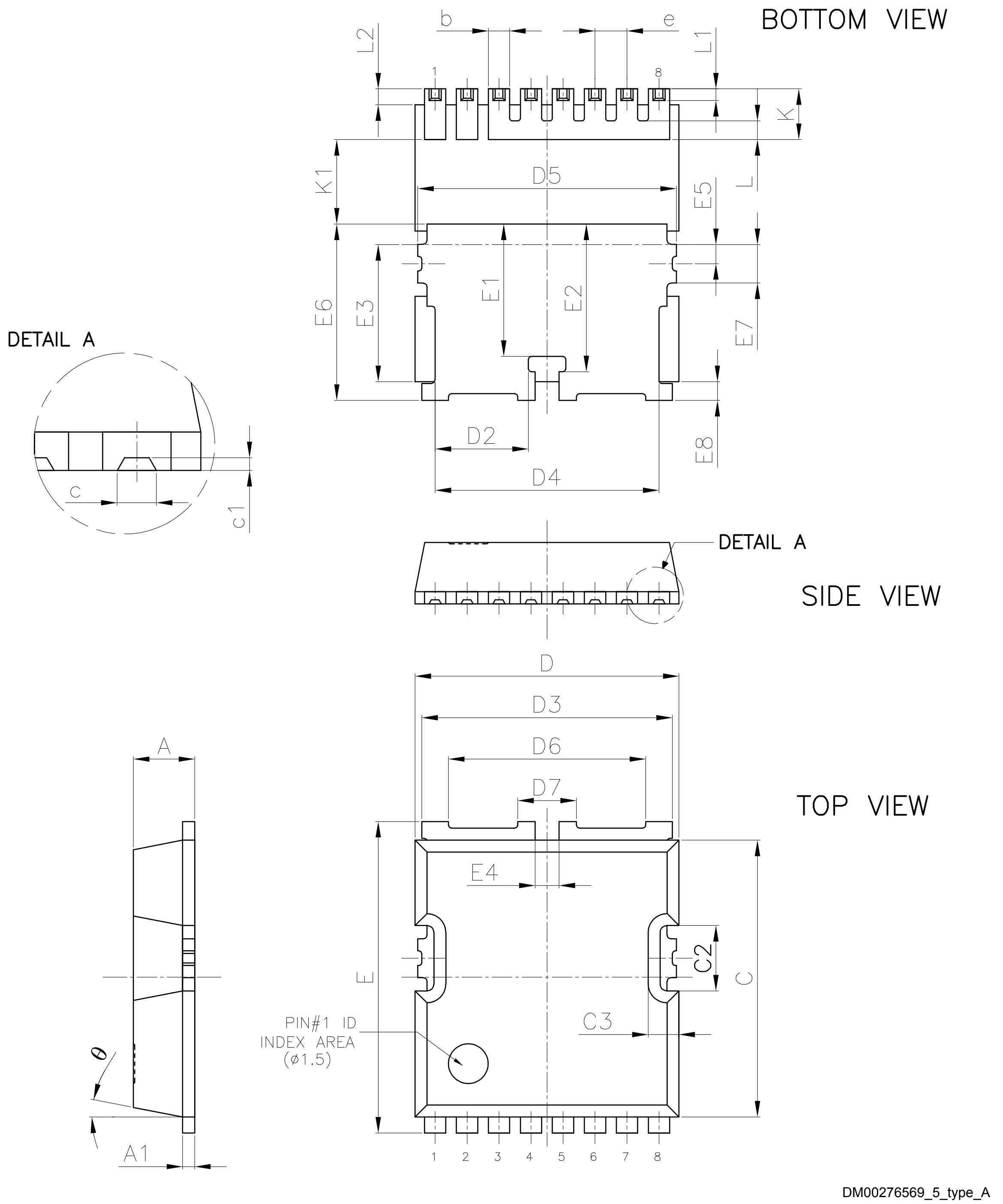
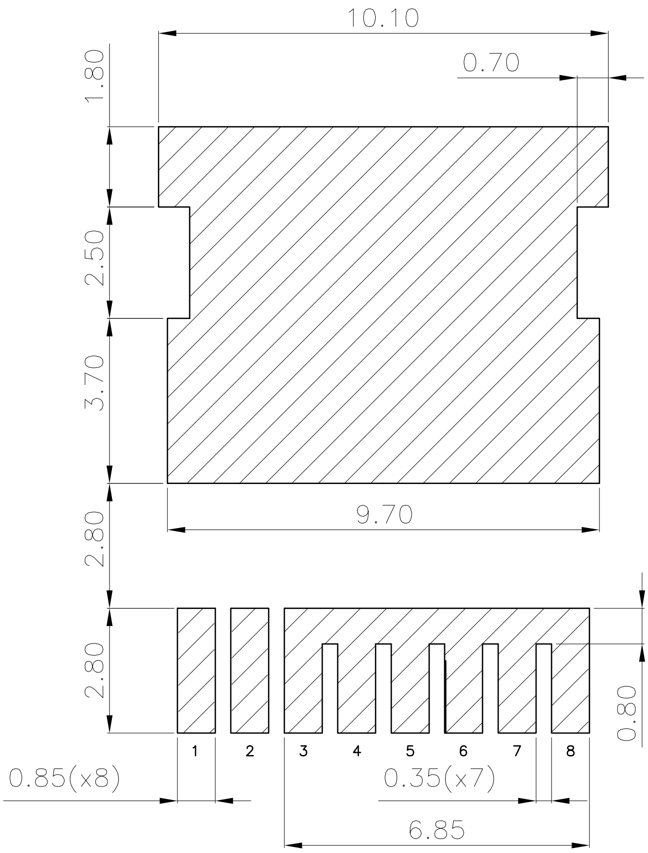


Table 8. **TO-LL type A package mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	2.20	2.30	2.40
A1	0.40	0.48	0.60
b	0.70	0.80	0.90
c		0.46	
c1		0.15	
C	10.28	10.38	10.48
C2	2.35	2.45	2.55
C3		1.16	
D	9.80	9.90	10.00
D2	3.30	3.50	3.70
D3	9.30	9.40	9.50
D4	8.20	8.40	8.60
D5	9.50	9.70	9.90
D6		7.40	
D7		2.20	
e		1.20	
E	11.48	11.68	11.88
E1		4.96	
E2		5.54	
E3		5.14	
E4		0.90	
E5		0.72	
E6	6.41	6.61	6.81
E7		1.44	
E8	0.50	0.70	0.90
K	1.70	1.90	2.10
K1	2.70		
L		0.70	
L1		0.44	
L2	0.40	0.60	0.80
θ		11°	

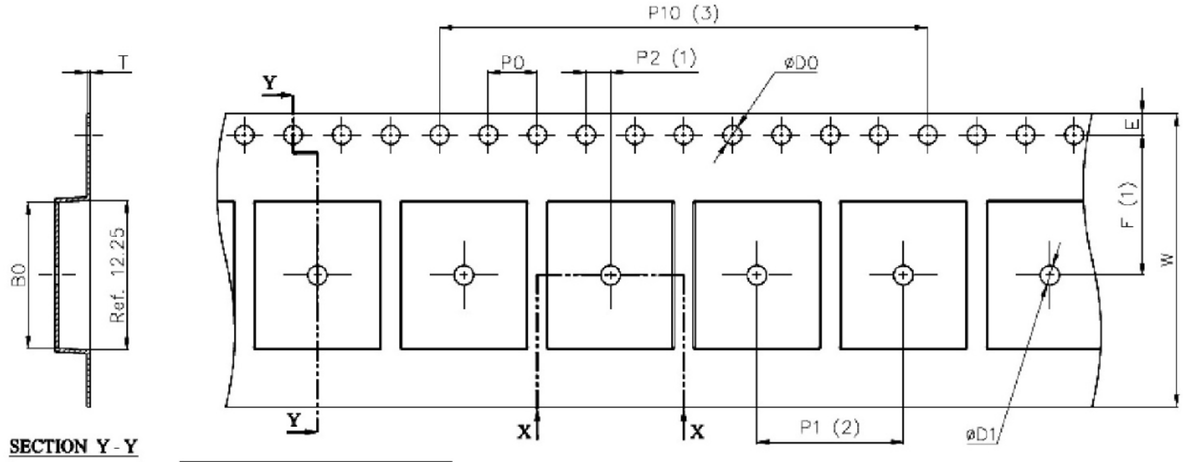
Figure 20. **TO-LL type A recommended footprint (dimensions are in mm)**



DM00276569_5_type_A_FP

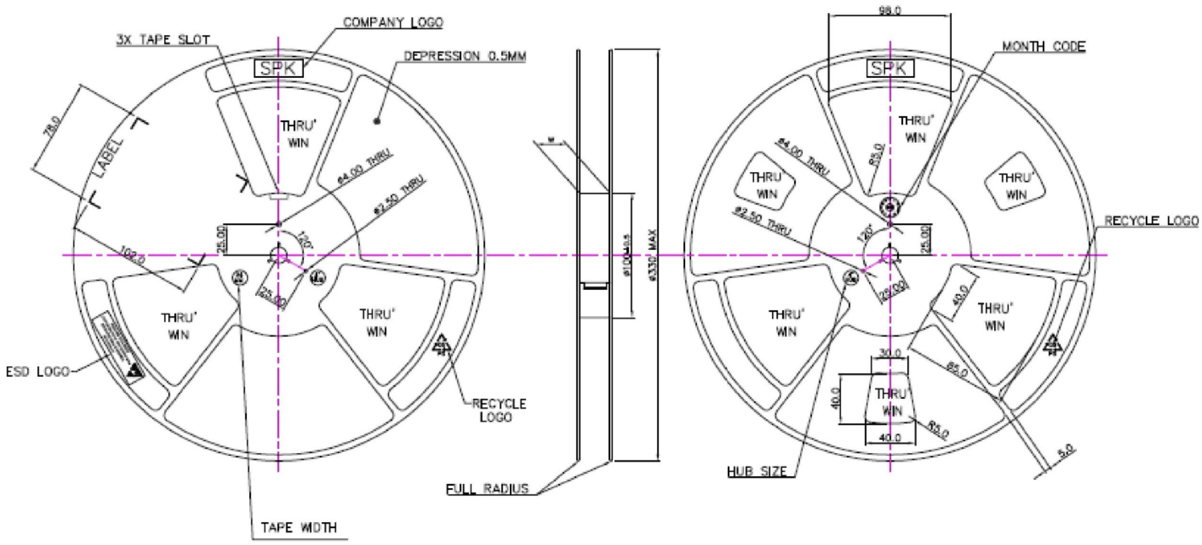
4.2 TO-LL packing information

Figure 21. Carrier tape outline and dimensions



Dimension List			
Annote	Millimeter	Annote	Millimeter
A0	10.20±0.10	P2	2.00±0.10
B0	11.98±0.10	P10	40.00±0.20
K0	2.60±0.10	E	1.75±0.10
D0	$1.50^{+0.10}_{-0}$	F	11.50±0.10
D1	1.60±0.10	W	24.00±0.30
P0	4.00±0.10	T	0.30±0.05
P1	12.00±0.10		

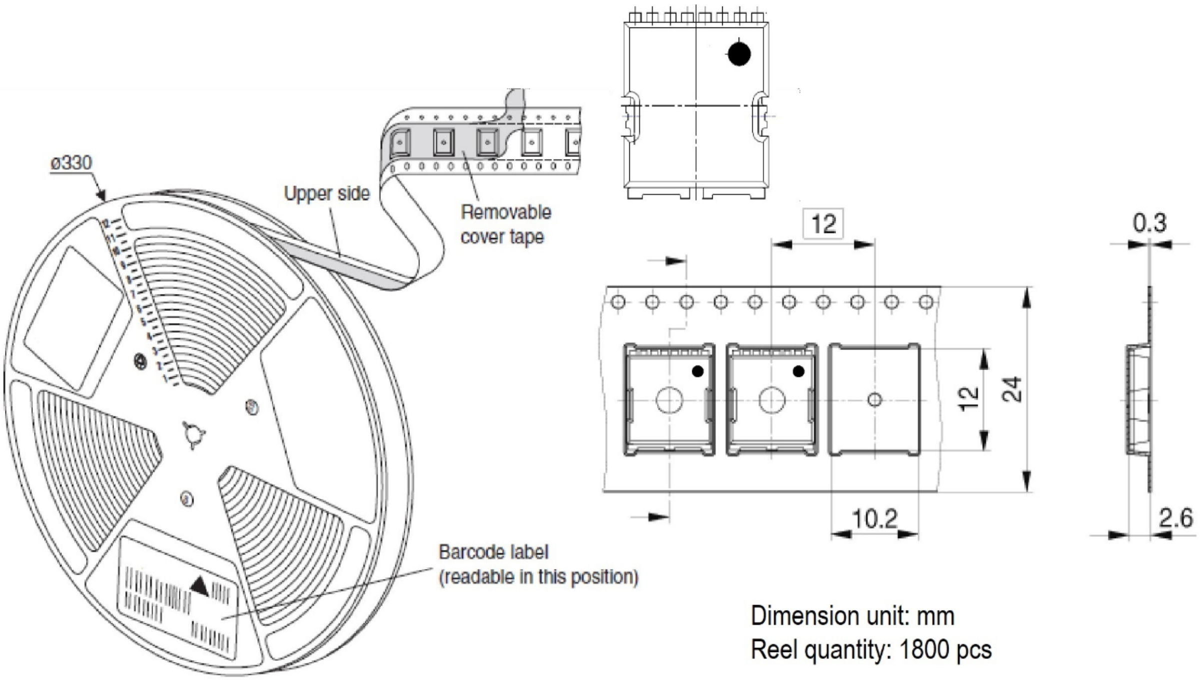
Figure 22. Reel outline and dimensions



SPECIFICATION							
TAPE WIDTH	W	U	X	V	Y	Z	P
24mm	24.4	1.50	24.5	20.0	0.55	6.00	2

Dimension unit: mm

Figure 23. TO-LL orientation in tape pocket



Revision history

Table 9. Document revision history

Date	Version	Changes
11-Jul-2018	1	Initial release.
05-May-2021	2	Updated title and Device summary in cover page. Updated Table 1. Absolute maximum ratings and Table 2. Thermal data. Updated Table 5. Dynamic. Updated Figure 5. Gate charge vs gate-source voltage. Updated Section 4 Package information. Minor text changes.

Contents